

Notice of References Cited	Application/Control No. 10/758,817	Applicant(s)/Patent Under Reexamination MARKS, RICHARD L.	
	Examiner Kent Wang	Art Unit 2622	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,061,507	06-2006	Tuomi et al.	345/611
	B	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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